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Understanding GaAs Native Oxides By Correlating Three Liquid Contact Angle Analysis (3LCAA) and High Resolution Ion Beam Analysis (HR-IBA) to X-Ray Photoelectron Spectroscopy (XPS) as Function of Surface Processing — ERRATUM

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In the title of this article¹, the chemical formula “GaAs” was misspelled. This has been corrected in the original article.

The publisher regrets this error.

Reference:

1. S. Ram, A.A. Chow, S. Khanna, N.C. Suresh, F.J. Ark, S.R. Narayan, A.R. Gurijala, J.M. Day, T. Karcher, R.J. Culbertson, S.D. Whaley, K.L. Kavanagh, and N. Herbots, MRS Advances 1 (2019).